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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Obsolete
Core Processor	8051
Core Size	8-Bit
Speed	48 MIPS
Connectivity	EBI/EMI, I²C, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, POR, PWM, Temp Sensor, WDT
Number of I/O	40
Program Memory Size	64KB (64K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	4.25K x 8
Voltage - Supply (Vcc/Vdd)	2.7V ~ 5.25V
Data Converters	A/D 32x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	Die
Supplier Device Package	-
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/c8051f380-gdi

Analog Peripherals

- **10-Bit ADC**
    - Up to 500 ksps
    - Built-in analog multiplexer with single-ended and differential mode
    - VREF from external pin, internal reference, or V_{DD}
    - Built-in temperature sensor
    - External conversion start input option
- **Two comparators**
- **Internal voltage reference**
- **Brown-out detector and POR Circuitry**

USB Function Controller

- USB specification 2.0 compliant
- Full speed (12 Mbps) or low speed (1.5 Mbps) operation
- Integrated clock recovery; no external crystal required for full speed or low speed
- Supports eight flexible endpoints
- 1 kB USB buffer memory
- Integrated transceiver; no external resistors required

On-Chip Debug

- On-chip debug circuitry facilitates full speed, non-intrusive in-system debug (No emulator required)
- Provides breakpoints, single stepping, inspect/modify memory and registers
- Superior performance to emulation systems using ICE-chips, target pods, and sockets

Voltage Supply Input: 2.7 to 5.25 V

- Voltages from 2.7 to 5.25 V supported using On-Chip Voltage Regulators

High Speed 8051 µC Core

- Pipelined instruction architecture; executes 70% of Instructions in 1 or 2 system clocks
- Up to 48 MIPS operation
- Expanded interrupt handler

Memory

- 4352 RAM
- 64 kB Flash; In-system programmable in 512-byte sectors

Digital Peripherals

- 40 Port I/O; All 5 V tolerant with high sink current
- Hardware enhanced SPI™, two I²C/SMBus™, and two enhanced UART serial ports
- Six general purpose 16-bit counter/timers
- 16-bit programmable counter array (PCA) with five capture/compare modules
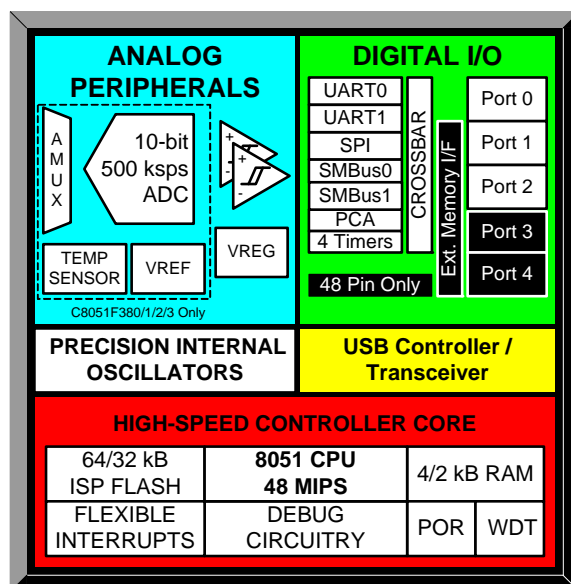- External Memory Interface (EMIF)

Clock Sources

- Internal Oscillator: ±0.25% accuracy with clock recovery enabled. Supports all USB and UART modes
- External Oscillator: Crystal, RC, C, or clock (1 or 2 Pin modes)
- Low Frequency (80 kHz) Internal Oscillator
- Can switch between clock sources on-the-fly

Temperature Range: –40 to +85 °C

Full Technical Data Sheet

- C8051F380/1/2/3/4/5/6/7

C8051F380-GDI

1. Ordering Information

Table 1.1. Product Selection Guide

Ordering Part Number	MIPS (Peak)	Flash Memory (kB)*	RAM (Bytes)	USB with 1k Endpoint RAM	SMBus/I²C	UARTs	Enhanced SPI	Timers (16-bit)	Programmable Counter Array	Digital Port I/Os	10-bit 500 ksps ADC	External Memory Interface (EMIP)	Internal Voltage Reference	Temperature Sensor	Analog Comparators	Package
C8051F380-GDI	48	64	4352	✓	2	2	✓	6	✓	40	✓	✓	✓	✓	2	Tested Die in Wafer Form
*Note: 1024 bytes reserved for factory use																

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2. Pin Definitions

Table 2.1 lists the pin definitions for the C8051F380-GDI. For a full description of the operation of each pin, refer to the C8051F380/1/2/3/4/5/6/7 data sheet.

Table 2.1. Pin Definitions for the C8051F380-GDI

Name	Physical Pad Number	Type	Description
V_{IO}	49	Power In	2.7–3.6 V Power Supply Voltage Input.
V_{DD}	50	Power Out	3.3 V Voltage Regulator Output (when 5 V regulator is used; otherwise it is a 2.7 to 3.6 V input).
GND	7		Ground.
$\overline{RST}$/ C2CK	12	D I/O D I/O	Device Reset. Open-drain output of internal POR or V_{DD} monitor. An external source can initiate a system reset by driving this pin low for at least 15 µs. Clock signal for the C2 Debug Interface.
C2D	13	D I/O	Bi-directional data signal for the C2 Debug Interface.
REGIN	51	Power In	5 V Regulator Input. This pin is the input to the on-chip voltage regulator.
VBUS	11	D In	VBUS Sense Input. This pin should be connected to the VBUS signal of a USB network. A 5 V signal on this pin indicates a USB network connection.
D+	8	D I/O	USB D+.
D-	9	D I/O	USB D–.
P0.0	6	D I/O or A In	Port 0.0.
P0.1	5	D I/O or A In	Port 0.1.
P0.2	4	D I/O or A In	Port 0.2.
P0.3	3	D I/O or A In	Port 0.3.
P0.4	2	D I/O or A In	Port 0.4.
P0.5	1	D I/O or A In	Port 0.5.
P0.6	48	D I/O or A In	Port 0.6.

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Table 2.1. Pin Definitions for the C8051F380-GDI (Continued)

Name	Physical Pad Number	Type	Description
P0.7	47	D I/O or A In	Port 0.7.
P1.0	46	D I/O or A In	Port 1.0.
P1.1	45	D I/O or A In	Port 1.1.
P1.2	44	D I/O or A In	Port 1.2.
P1.3	43	D I/O or A In	Port 1.3.
P1.4	42	D I/O or A In	Port 1.4.
P1.5	41	D I/O or A In	Port 1.5.
P1.6	40	D I/O or A In	Port 1.6.
P1.7	39	D I/O or A In	Port 1.7.
P2.0	38	D I/O or A In	Port 2.0.
P2.1	37	D I/O or A In	Port 2.1.
P2.2	36	D I/O or A In	Port 2.2.
P2.3	35	D I/O or A In	Port 2.3.
P2.4	34	D I/O or A In	Port 2.4.
P2.5	33	D I/O or A In	Port 2.5.
P2.6	32	D I/O or A In	Port 2.6.
P2.7	31	D I/O or A In	Port 2.7.
P3.0	30	D I/O or A In	Port 3.0.

Table 2.1. Pin Definitions for the C8051F380-GDI (Continued)

Name	Physical Pad Number	Type	Description
P3.1	29	D I/O or A In	Port 3.1.
P3.2	28	D I/O or A In	Port 3.2.
P3.3	27	D I/O or A In	Port 3.3.
P3.4	26	D I/O or A In	Port 3.4.
P3.5	25	D I/O or A In	Port 3.5.
P3.6	24	D I/O or A In	Port 3.6.
P3.7	22	D I/O or A In	Port 3.7.
P4.0	21	D I/O or A In	Port 4.0.
P4.1	20	D I/O or A In	Port 4.1.
P4.2	19	D I/O or A In	Port 4.2.
P4.3	18	D I/O or A In	Port 4.3.
P4.4	17	D I/O or A In	Port 4.4.
P4.5	16	D I/O or A In	Port 4.5.
P4.6	15	D I/O or A In	Port 4.6.
P4.7	14	D I/O or A In	Port 4.7.

C8051F380-GDI

3. Bonding Instructions

Table 3.1. Bond Pad Coordinates (Relative to Center of Die)

Physical Pad Number	Example Package Pin Number (QFP-48)	Package Pin Name	Physical Pad X (µm)	Physical Pad Y (µm)
1	1	P0.5	−978	−1021
2	2	P0.4	−836	−1021
3	3	P0.3	−659	−1021
4	4	P0.2	−516	−1021
5	5	P0.1	−359	−1021
6	6	P0.0	−217	−1021
7	7	GND	−91	−1021
8	8	D+	124	−1020
9	9	D−	434	−1020
10	Reserved*	—	666	−1021
11	12	VBUS	947	−1021
12	13	RST/C2CK	1181	−818
13	14	C2D	1181	−676
14	15	P4.7	1181	−519
15	16	P4.6	1181	−377
16	17	P4.5	1181	−199
17	18	P4.4	1181	−57
18	19	P4.3	1181	100
19	20	P4.2	1181	242
20	21	P4.1	1181	419
21	22	P4.0	1181	561
22	23	P3.7	1181	718
23	Reserved*	—	1177	850
24	24	P3.6	966	1020
25	25	P3.5	809	1020
26	26	P3.4	667	1020

*Note: Pins marked "Reserved" should not be connected.

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Table 3.1. Bond Pad Coordinates (Relative to Center of Die) (Continued)

Physical Pad Number	Example Package Pin Number (QFP-48)	Package Pin Name	Physical Pad X (µm)	Physical Pad Y (µm)
27	27	P3.3	510	1020
28	28	P3.2	368	1020
29	29	P3.1	211	1020
30	30	P3.0	69	1020
31	31	P2.7	−88	1020
32	32	P2.6	−231	1020
33	33	P2.5	−387	1020
34	34	P2.4	−530	1020
35	35	P2.3	−686	1020
36	36	P2.2	−829	1020
37	37	P2.1	−985	1020
38	38	P2.0	−1181	822
39	39	P1.7	−1181	666
40	40	P1.6	−1181	523
41	41	P1.5	−1181	367
42	42	P1.4	−1181	224
43	43	P1.3	−1181	67
44	44	P1.2	−1181	−75
45	45	P1.1	−1181	−232
46	46	P1.0	−1181	−374
47	47	P0.7	−1181	−531
48	48	P0.6	−1181	−818
49	10	VDD	625	−802
50	10	VDD	700	−802
51	11	REGIN	775	−802
52	Reserved*	—	280	−634
53	Reserved*	—	490	−634
54	Reserved*	—	917	−634

*Note: Pins marked "Reserved" should not be connected.
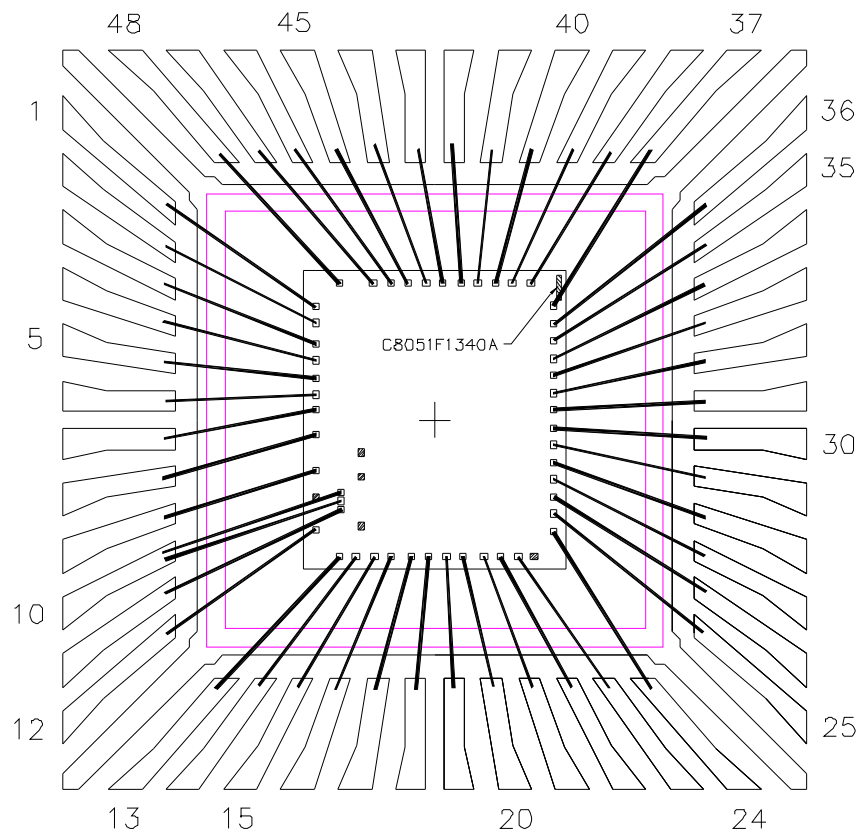
Figure 3.1. Die Bonding (QFP-48)

Table 3.2. Wafer and Die Information

Wafer ID	C8051F1340A
Wafer Dimensions	8 in
Die Dimensions	2.26 mm x 2.58 mm
Wafer Thickness	12 mil ±1 mil
Wafer Identification	Notch
Scribe Line Width	80 µm
Die Per Wafer*	Contact Sales for info
Passivation	Standard
Wafer Packaging Detail	Wafer Jar
Bond Pad Dimensions	60 µm x 60 µm
Maximum Processing Temperature	250 °C
Electronic Die Map Format	.txt
Bond Pad Pitch Minimum	75 mil
*Note: This is the Expected Known Good Die yielded per wafer and represents the batch order quantity (one wafer).	

4. Wafer Storage Guidelines

It is necessary to conform to appropriate wafer storage practices to avoid product degradation or contamination.

- Wafers may be stored for up to 18 months in the original packaging supplied by Silicon Labs.
- Wafers must be stored at a temperature of 18–24 °C.
- Wafers must be stored in a humidity-controlled environment with a relative humidity of <30%.
- Wafers should be stored in a clean, dry, inert atmosphere (e.g. nitrogen or clean, dry air).

DOCUMENT CHANGE LIST

Revision 1.0 to Revision 1.1

■ Changed Wafer Packaging Detail to "Wafer Jar"
  in Table 3.2 on page 9.
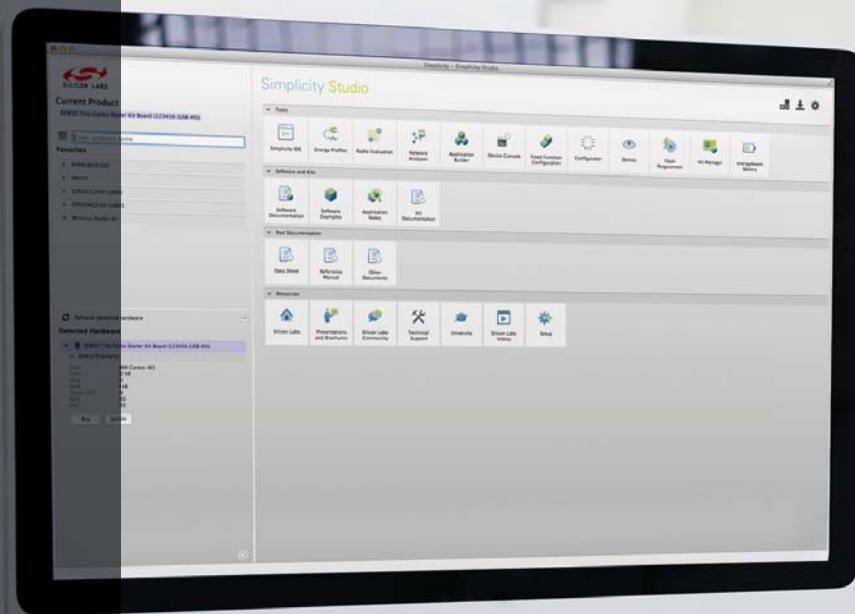
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